

TEST REPORT ON

SMF VRLA BATTERY

OB 18-12

12V/18 Ah



Material Appraisal Laboratory

ASSOCIATED ELECTRONICS RESEARCH FOUNDATION

C-53, Phase-II, Noida-201 305 Distt. Gautam Budh Nagar (U.P.)

E-mail: aerfnoida@yahoo.in Website: www.aerfindia.com Telefax: $\begin{cases} 0120-3047725 / 726 \\ 0120-3047727 / 728 \\ 0120-3047727 / 729 \\ 0120-2562355/2233 \end{cases}$



Deviation if, any





Phones: 0120 - 4543789, 4543790 E-mail: aerf@aerfindia.com, serfacida@yahoo.in Web.: www.aerfindia.com CIN: U00000DL1981NPL011318

Associated Electronics Research Foundation

C-53, Phase-II Noida-201 305 (Recognised by DSIR, Govt. of India) Centre for Research, Calibration & Testing (An NABL Accredited Laboratory in Electrical & Electronics Testing)

Test Report

T	est Report	
Test Report Number	Date	Page No.
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INDENTOR (Name & address of the organisation sending items for testing)	*	OKAYA Power Pvt Ltd. D- 7, Udyog Nagar, Rohtak Road, New Delhi – 110041
Indentor 's reference(Date of Receipt) Description and identification of the item(as provided by the indentor)	:	12/ 06 /2017
i) Nomenclature of the product	:	SMF / VRLA Battery
ii) Model/Sr No. iii) Value/Tolerance	:	OB 18-12 12 V / 18Ah / 20Hrs
iv) Serial No.		IAUSS06201004855 & IAUSS06201004859
v) Manufacturer's name	;	OKAYA Power Pvt Ltd
vi) Year of manufacture	:	2017
vii) Trade Mark/Make	:	OKAYA
viii) Number of samples		Qty 2
ix) Condition of samples when submitted	:	Ok
a) Applicable Specification		As per JIS C 8702-(Part 1): 2009
b) Samples were grouped and numbered as under		As per indentor
c) Environmental Conditions	1	26°C / 57% R.H
d) Date of Performance of Test:		12/06/2017 to 16/06/2017

Regd. Office: B-7/2, Okhia Industrial Area, Phase-II, New Delhi-110 020

None

Authorized Signatory

POOJA JAIN

Quality Manager

Associated Electronics Resitarch Foundation
C-53, Phase-II, NOIDA U.P.-201305







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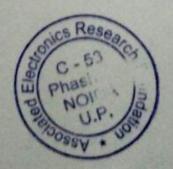
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6. Tests Conducted:

Sr No	Test Parameter	Test Standar d with Cl No	Test Condition	Observation with test data	Pass / Fail	Remarks
1	Capacity 20 hrs	As per JIS C 8702-1 : 2009 C1 5.1 (a) & 7.1	After fully charged as per JIS C 8702-1: 2009, Cl 6.1 battery kept for 5 to 24 hrs at 25°C ±2°C discharge current I ₂₀ = 0.9 amp& final voltage 6 x 1.75 = 10.5V Capacity = t x I ₂₀	Time taken to reach 10.5V End of voltage is 23.93hr Capacity = 23.93hr x 0.9A = 21.54Ah	Pass	
2	High Rate Discharge	As per JIS C 8702-1 : 2009 Cl 5.2 & 7.2	Discharge Current 20 x l ₂₀ = 18Amp. End of Voltage 9.6Volt. At 25°C±2°C discharge time should be 27 mins minimum	Discharge time for end of voltage 9.6Volt is 38.56 mins	Pass	



Authorized Signatory Pools

Qually Manager
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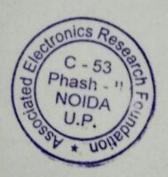
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	Date 16/06/2017	

7. Remarks:

1. This Report refers to the particular item submitted for testing.

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The results reported in the report are valid at the time of and under the stated conditions of measurement.



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Quality Manager
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